DDR/LPDDR Post Process Compliance Tool

User Guide



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Keysight Technologies 1900 Garden of the Gods Road Colorado Springs, CO 80907 USA

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Safety Notices

CAUTION

A CAUTION notice denotes a hazard. It calls attention to an operating procedure, practice, or the like that, if not correctly performed or adhered to, could result in damage to the product or loss of important data. Do not proceed beyond a CAUTION notice until the indicated conditions are fully understood and met.

WARNING

A WARNING notice denotes a hazard. It calls attention to an operating procedure, practice, or the like that, if not correctly performed or adhered to, could result in personal injury or death. Do not proceed beyond a WARNING notice until the indicated conditions are fully understood and met.

Safety Summary

The following general safety precautions must be observed during all phases of operation of this instrument. Failure to comply with these precautions or with specific warnings or operating instructions in the product manuals violates safety standards of design, manufacture, and intended use of the instrument. Keysight Technologies assumes no liability for the customer's failure to comply with these requirements. Product manuals are provided with your instrument on CD-ROM and/or in printed form. Printed manuals are an option for many products. Manuals may also be available on the Web. Go to www.keysight.com and type in your product number in the Search field at the top of the page.

General

Do not use this product in any manner not specified by the manufacturer. The protective features of this product may be impaired if it is used in a manner not specified in the operation instructions.

Before Applying Power

Verify that all safety precautions are taken. Make all connections to the unit before applying power. Note the instrument's external markings described in "Safety Symbols".

Ground the Instrument

If your product is provided with a grounding type power plug, the instrument chassis and cover must be connected to an electrical ground to minimize shock hazard. The ground pin must be firmly connected to an electrical ground (safety ground) terminal at the power outlet. Any interruption of the protective (grounding) conductor or disconnection of the protective earth terminal will cause a potential shock hazard that could result in personal injury.

Fuses

See the user's guide or operator's manual for information about line-fuse replacement. Some instruments contain an internal fuse, which is not user accessible.

Do Not Operate in an Explosive Atmosphere

Do not operate the instrument in the presence of flammable gases or fumes.

Do Not Remove the Instrument Cover

Only qualified, service-trained personnel who are aware of the hazards involved should remove instrument covers. Always disconnect the power cable and any external circuits before removing the instrument cover.

Cleaning

Clean the outside of the instrument with a soft, lint-free, slightly dampened cloth. Do not use detergent or chemical solvents.

Do Not Modify the Instrument

Do not install substitute parts or perform any unauthorized modification to the product. Return the product to an Keysight Sales and Service Office for service and repair to ensure that safety features are maintained.

In Case of Damage

Instruments that appear damaged or defective should be made inoperative and secured against unintended operation until they can be repaired by qualified service personnel.

CAUTION

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WARNING

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Safety Symbols

Table 1 Safety Symbol

Symbol	Description
===	Direct current
\sim	Alternating current
$\overline{\sim}$	Both direct and alternating current
₃ ~	Three phase alternating current
₃ ~	Three phase alternating current
-	Earth ground terminal
	Protective earth ground terminal
///	Frame or chassis ground terminal
	Terminal is at earth potential
\triangle	Equipotentiality
N	Neutral conductor on permanently installed equipment
L	Line conductor on permanently installed equipment
	On (mains supply)
<u>Ф</u>	Off (mains supply)
山	Stand by (mains supply). The instrument is not completely disconnected from the mains supply when the power switch is in the stand by position
_	In position of a bi-stable push switch

Combal	Description
Symbol	Description
	Out position of a bi-stable push switch
	Equipment protected throughout by DOUBLE INSULATION or REINFORCED INSULATION
\triangle	Caution, refer to accompanying documentation
	Caution, risk of electric shock
(Do not apply around or remove from HAZARDOUS LIVE conductors
4	Application around and removal from HAZARDOUS LIVE conductors is permitted
	Caution, hot surface
	lonizing radiation
CAT I	IEC Measurement Category I
CAT II	Measurement Category II
CAT III	Measurement Category III
CAT IV	Measurement Category IV

Compliance and Environmental Information

Table 2 Compliance and Environmental Information

Safety Symbol	Description
③ ∘	\ensuremath{CSA} is the Canadian certification mark to demonstrate compliance with the Safety requirements.
	The C-tick mark is a registered trademark of the Spectrum Management Agency of Australia. This signifies compliance with the Australia EMC Framework regulations under the terms of the Radio Communication Act of 1992.
CE	CE compliance marking to the EU Safety and EMC Directives. ISM GRP-1A classification according to the international EMC standard. ICES/NMB-001 compliance marking to the Canadian EMC standard.

DDR/LPDDR Post Process Compliance—At a Glance

The DDR/LPDDR Post Process Compliance Tool evaluates the captured DDR/LPDDR data against a set of user-defined limits to help you validate that a memory system is operating properly. The bus types supported by this tool are:

- DDR1/2/3/4
- LPDDR1/2/3/4

The automated test application guides you through the process of selecting and configuring tests, running tests, and evaluating the test results.

The application assumes that the Keysight logic analysis system has already been set up to properly capture DDR data.

To use the automated test application, see:

- · Chapter 2, "Starting the DDR/LPDDR Post Process Compliance Tool" on page 15
- · Chapter 3, "Configuring Tests" on page 19
- · Chapter 4, "Setting Up the Test Environment" on page 27
- · Chapter 5, "Selecting Tests" on page 29
- · Chapter 6, "Running Tests" on page 33
- · Chapter 7, "Automating the Tests" on page 37
- · Chapter 8, "Viewing Results" on page 41
- Chapter 9"Viewing/Exporting/Printing the Report" on page 45
- Chapter 10 "Saving Test Projects" on page 51
- · Chapter 11, "Creating or Opening a Test Project" on page 53

Contents

	Safety Summary 3
	Compliance and Environmental Information 6
	DDR/LPDDR Post Process Compliance—At a Glance 7
1	About the Tool
2	Starting the DDR/LPDDR Post Process Compliance Tool
	To Toggle between the Toolbar 17
3	Configuring Tests
	To set the test limits 20
	To create/ed it limit sets 24
	To activate/refresh limit sets 25
4	Setting Up the Test Environment
5	Selecting Tests
6	Running Tests
	To set the display preferences 36
7	Automating the Tests
	Prerequisites 37 Automation by Scripts 38 Automation by Files 39
8	Viewing Results
Ū	To change margin thresholds 43
9	Viewing/Exporting/Printing the Report
	To export the report 47
	To print the report 49

10 Saving Test Projects

To set AutoRecovery preferences 52

11 Creating or Opening a Test Project

To set load preferences 54

Index

1 About the Tool

Overview of the tests

There are two types of tests:

- Tests which check for timing violations
- · Tests which check for illegal DDR state transitions

The test limits can be (and must be) configured by the user.

The provided timing violation tests include:

Parameter	Description	Test
tRAS _{max}	Row Active time ACTIVATE to PRECHARGE/Auto-PRECHARGE	must be < tRASmax
tRAS _{min}	Row Active time ACTIVATE to PRECHARGE/Auto-PRECHARGE	must be > tRASmin
tRP	PRECHARGE to any other command (same bank)	must be > tRP
tCCD	Time between any read or write command	must be > tCCD
tRRD	ACTIVATE to ACTIVATE (any bank)	must be >= tRRD
tFAW	Time for four ACTIVATEs (any bank)	must be >= tFAW
tRFC	REFRESH to REFRESH or ACTIVATE	must be > tRFC
tDARW	ACTIVATE to external READ/WRITE	must be > tDARW
tDRP	Read to Precharge/AutoPrecharge	must be > tDRP
tDRW	Read to Write	must be > tDRW
tDWP	Write to Precharge/AutoPrecharge	must be > tDWP
tDWR	Write to Read	must be > tDWR

Description
READ or WRITE to an inactive row
REFRESH to an active bank
ACTIVATE to an active bank

Compatibility

The DDR/LPDDR Post Process Compliance Tool works for most DDR, DDR2, DDR3, DDR4, LPDDR, LPDDR2, LPDDR3 and LPDDR4 systems.

The tool is not able to fully model systems which use the following optional DDR features:

- · Partial Array Self-Refresh (PASR)
- · Auto Self-Refresh (ASR)
- · On-the-fly Burst Length switching

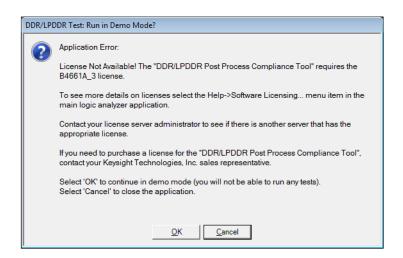


About the software

The Post Process Compliance Tool is part of the Keysight B4661A DDR/LPDDR Toolset package. This tool requires that you install the Logic and Protocol Analyzer software version 6.2 or higher. Versions prior to 6.2 do not support this tool.

Software License

The DDR/LPDDR Post Process Compliance Tool requires B4661A_3 license to operate. If this license is not installed in your system, the following license error dialog box is displayed while launching the DDR/LPDDR Post Process Compliance Tool application.



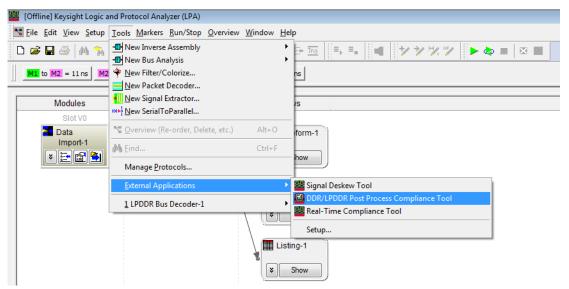
When you are launching the DDR/LPDDR Post Process Compliance Tool for the first time, the Keysight Technologies Software End User License Agreement dialog box appears. You can read the agreement and choose to agree or disagree before proceeding further to use the DDR/LPDDR Post Process Compliance Tool.



1 About the Tool

2 Starting the DDR/LPDDR Post Process Compliance Tool

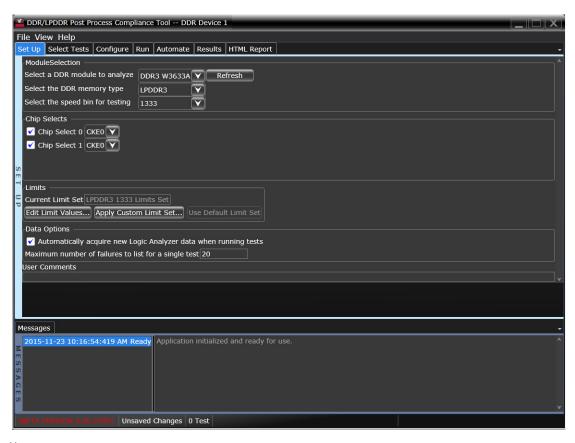
From the logic analysis system's main menu, choose **Tools > External Applications > DDR/LPDDR Post Process Compliance Tool**.



The DDR/LPDDR Post Process Compliance Tool window appears.







See Also · "To Toggle between the Toolbar" on page 17

Next • "Creating or Opening a Test Project" on page 53

To Toggle between the Toolbar

To toggle between the toolbars, you can click and drag the toolbars accordingly. To keep the default display for the toolbars, select **View>Preferences>Tab Layout** from the menu.

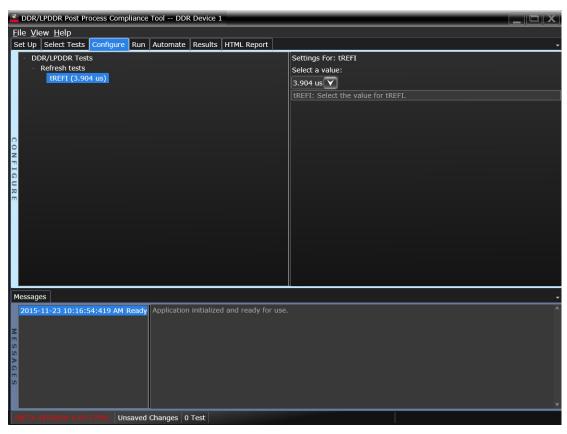


2 Starting the DDR/LPDDR Post Process Compliance Tool

3 Configuring Tests

You must configure a set of limits in **Configure** tab before you can run any tests.

These limits describe the memory part you are using and certain characteristics of the memory bus.



You can load, edit, and apply limits in Limits menu.

See Also

- "To set the test limits" on page 20 (for information on how to calculate the limits)
- "To create/edit limit sets" on page 24 (for information on how to enter and save the limits)
- "To activate/refresh limit sets" on page 25 (for information on how to load a limit set which you have saved)



To set the test limits

All timing violation tests are based on compliance limits that are specified by the user. Specify these limits based on the specific DDR memory parts you are using. Limits will vary depending on:

- Memory technology (DDR2, DDR3)
- · Speed grade
- Clock speed
- · Part density
- User selected options such as Additive Latency and burst length

Units

Some times must be entered in seconds (s). If the data sheet expresses these limits in terms of clock cycles, you will need to convert those limits to seconds.

Each logic analyzer sample has a timestamp. Results will be calculated by subtracting the time stamp of the first event from the timestamp of the second event. Note that the time stamps are only as good as the time stamp resolution of the logic analyzer card being used (this resolution may be as coarse as 2ns; see the Specifications and Characteristics in the logic analyzer's Online help for details). The elapsed time includes time during which the DDR clock is inactive.

Other times must be entered as a number of clock cycles (CK). Results will be calculated by counting the number of logic analyzer samples between the two events.

Additive latency (AL) is normally expressed as a number of clocks (CK). For some calculations, you will need to convert AL to seconds (s) by dividing by the clock rate.

Burst length (BL) is simply an integer (4 or 8).

Definitions of the limits

You will need to look up some of the limits from the part data sheet. You will then calculate values for the derived limits.

Keysight suggests using the formulas here to compute the derived limits. However, it is entirely the responsibility of the user to choose limits that are appropriate for the intended application.

Here are the limits you need to specify:

Parameter	Description	Unit	Suggested Definition	Reference
tRAS _{max}	Row Active time ACTIVE to PRECHARGE	S	Part dependent (9 * tREFI)	Data Sheet (tREFI). See DDR3 (see page 24) page 147.
tRAS _{min}	Row Active time ACTIVE to PRECHARGE	S	Part dependent	Data Sheet
tDARW	Min ACT to external READ/WRITE	S	tRCD-AL	DDR2 (see page 23) 3.5 / DDR3 (see page 24) 12.3
tRP	Row Precharge time min PRECHARGE to any other command (same bank)	S	Part dependent	Data Sheet
tDRP	Min Read to Precharge	СК	DDR2: AL + BL/2 + max (tRTP, 2CK) -2CK DDR3: AL + tRTP	DDR2 (see page 23) 3.7.1 / DDR3 (see page 24) 4.13.3
tDRW	Min Read to Write	СК	DDR2: BL/2 + 2CK DDR3: BL4: RL + CCD/2 + 2CK - WL DDR3: BL8: RL + CCD + 2CK - WL	DDR2 (see page 23) figure 35 / DDR3 (see page 24) figure 35, 36
tRFC	REFRESH command time. min time REFRESH to REFRESH or ACTIVATE	S	Part dependent	Data Sheet

Parameter	Description	Unit	Suggested Definition	Reference
tDWP	Min Write to Precharge	СК	WL + BL/2 + tWR	DDR2 (see page 23) 3.7.2 / DDR3 (see page 24) Figure 49, 50
tDWR	Min Write to Read	СК	DDR2: CL -1 + BL/2 + tWTR DDR3: WL + BL/2 + tWTR	DDR2 (see page 23) Figure 41 / DDR3 (see page 24) Figure 53, 56
tCCD	CAS to CAS delay min time between any read or write command	CK	Part dependent	Data Sheet
tRRD	Min time between two ACTIVATE commans (different banks)	S	Part dependent	Data Sheet
tFAW	Min time for four ACTIVATE commands (different banks)	S	Part dependent	Data Sheet

Values used to To calculate the limits, you will need to look up or calculate the following values: calculate the limits

Parameter	Description	Unit	Suggested Definition	Reference
AL	Additive Latency	CK, s	User selection	System Design
BL	Burst Length		User selection	System Design
CL	CAS (Read) Latency	CK	Part dependent	Data Sheet
CWL	CAS Write Latency	CK	Part dependent	Data Sheet
RL	Read Latency	СК	AL + CL	DDR3 (see page 24) 3.4.3.4
WL	Write latency	СК	AL + CWL	DDR3 (see page 24) 3.4.3.4
tRCD	RAS to CAS Delay (ACT to internal R/W)	S	Part dependent	Data Sheet
tREFI	Refresh Interval; average time between Refresh commands	S	Part dependent	Data Sheet
tRTP	Internal Read to Precharge	S	Part dependent (max 4CK or 7.5ns)	Data Sheet
tWR	Internal Write Recovery	S	Part dependent	Data Sheet
tWTR	Internal Write to internal Read	S	Part dependent (max 4CK or 7.5ns)	Data Sheet

External Read/Write + AL = Internal Read/Write

Naming conventions

Limits which are normally expressed as maximum or minimum times have names beginning with 't'.

The names of derived timing limits begin with 'tD'. Derived limits are not usually specified directly in the part data sheet. In general, you will compute these from the standard timing parameters.

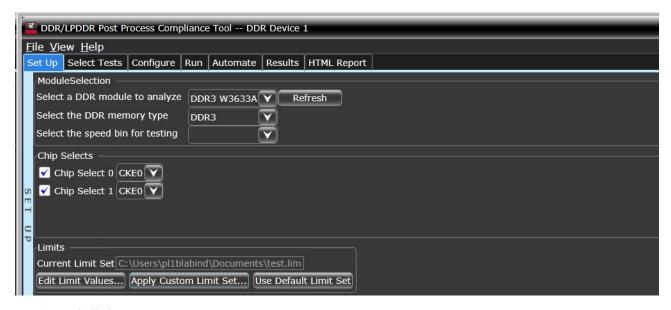
Limits which are normally expressed as a number of clock cycles have no prefix. In some cases, you may need to convert these to seconds for use by the tool.

Customizing the limits

The definitions are suggestions based on the DDR2/3 standards. There is no requirement that the user must set the limits to those specified in the data sheet or in the JEDEC standard. You can set the limits however you like, depending on the goals of your testing.

To load and view the limits, you can either use the default limit set or use customized limit sets.

If you are using customized limit sets, you can select the customized compressed archived files (.lim) from your local system and click **Apply Custom Limit Set...** in **Limits** section.



Example limits

An example limit set is supplied with the validation tool. The example is based on a DDR800 part with 6-6-6 timing.

Example part:

- Data sheet: MICRON DDR3 MT41J256-32 Me x 4 x 8 Banks PDF: 09005aef82f1e6e2 Rev. M 9/08 EN
- Speed Grade 25 (6-6-6)
- Clock 400 MHz (2.5ns)
- · Data Rate 800 MT/s
- · Temperature 0-85C

Parameter	Value	Reference
tREFI	7.8 us (low temp)	Data Sheet, page 71
tRAS _{max}	70.2us	Data Sheet (tREFI), page 63
tRAS _{min}	37.5ns	Data Sheet, page 30
tRP	15ns	Data Sheet, page 30
tCCD	4CK (10ns)	Data Sheet, page 70
tRRD	10ns	Data Sheet, page 30
tFAW	50ns	Data Sheet, page 30
tRFC	110ns	Data Sheet, page 30
tRCD	15ns	Data Sheet, page 30
tRTP	10ns	Data Sheet, page 70
tWR	15ns	Data Sheet, page 70

Parameter	Value	Reference
tWTR	10ns	Data Sheet, page 70
AL	Ons (OCK)	User selected (MR1, 0 means no additive latency)
BL	10ns (8 bursts)	User selected (MR0)
CL	6CK (15ns)	Data Sheet, page 30 (MR0)
CWL	5CK (12.5ns)	Data Sheet, page 116 (MR2)

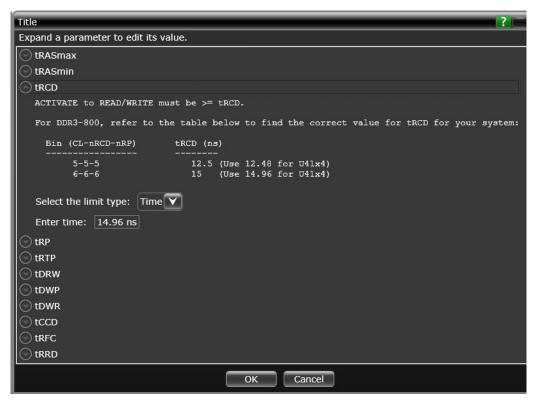
Parameter	Value
RL	6CK (15ns)
WL	5CK (12.5ns)
tDARW	15ns
tDRP	10ns
tDRW	17.5ns
tDWP	32.5ns
tDWR	27.5ns

- References · DDR2 JEDEC Standard 79-2E, April 2008
 - DDR3 JEDEC Standard 79-3C, November 2008

To create/edit limit sets

You can create new limit sets by modifying existing limit sets and saving them to new files.

- 1 From the DDR/LPDDR Post Process Compliance Tool's main page, choose **Edit Limit Values...** in **Limits** section.
- 2 In the Create/Edit User-Defined Limit Set dialog, double-click on the required test for which you want to edit the limits.



- 3 Modify the limit as desired.
- 4 Repeat the last two steps until all limits requiring change are modified.
- 5 Click **OK** to save your custom limit set to a file. Enter the file name in the Save File As dialog.
- Now, you can activate your newly-created limit set for use in the next run. See "To activate/refresh limit sets" on page 25.

When Loading Projects

When you load a project, the application will attempt to restore the limit set that was in use at the time the project was saved.

See Also

• "To set the test limits" on page 20 (for information on how to calculate the limits)

To activate/refresh limit sets

To load a previously defined limit set:

- 1 From the DDR/LPDDR Post Process Compliance Tool's menu, click Activate/Refresh limit set....
- 2 In the Activate/Refresh Compliance Limit Set dialog, select one of the official limit sets or a user-defined limit set.



3 Click OK.

NOTE

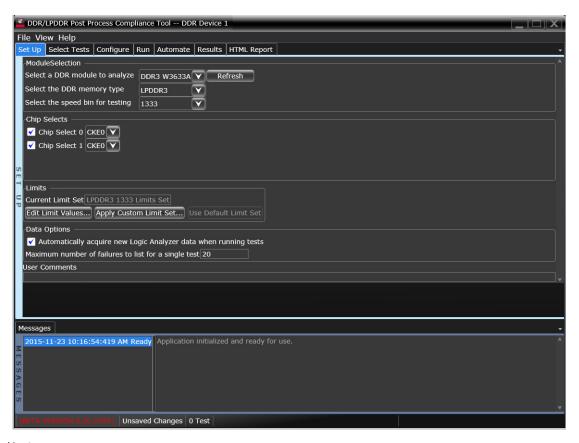
If you have existing test results when you activate a different limit set, the application examines your results to see if any of them would experience a limit change when the different limit set is loaded. If any results would be affected in this way, the application tells you which ones they are and warns that they must be deleted.

3 Configuring Tests

4 Setting Up the Test Environment

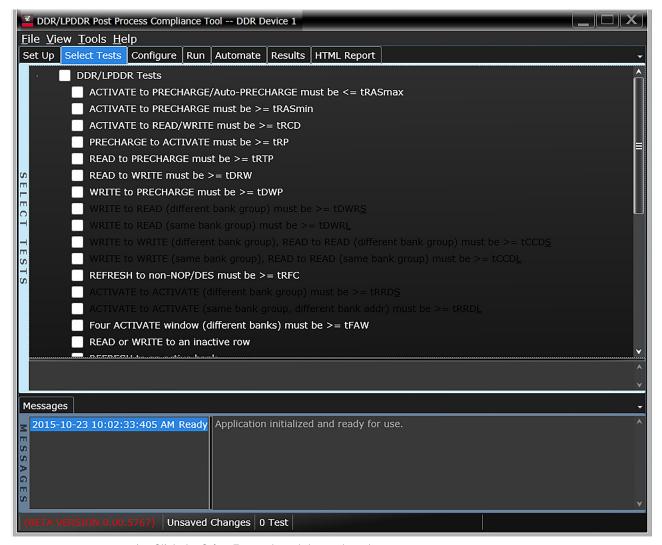
- 1 Click the **Set Up** tab.
- 2 If more than one DDR bus decoder exists in the logic analysis system setup, select which one to use for the compliance tests from the **Select a DDR module to analyze** listbox.
 - If only one decoder exists, it will be selected automatically.
 - If needed, click **Refresh** to update the list. You may need to refresh the list and select a new decoder if you load a new logic analyzer configuration file, or whenever you add or remove a decoder.
- 3 Select the DDR memory type. The DDR/LPDDR Post Process Compliance Tool can work with any of the following memory bus standards.
 - DDR1/2/3 /4
 - LPDDR1/2/3/4
- 4 From the **Set Up** section, select whether or not you want the tool to automatically acquire new data when compliance tests are run. Whether you plan to run tests once or multiple times, the selection of this checkbox instructs the tool to first run the logic analyzer for data acquisition. When the data acquisition run is complete, the tool starts post processing the newly acquired data by running the selected tests. If you plan to run the tests multiple times or forever, then you must select this checkbox to ensure that the tool runs the logic analyzer repetitively for data acquisition and then acquires the new data automatically for post processing.
 - Deselecting this checkbox instructs the tool to use the already acquired data for post processing. The tool does not run the logic analyzer for data acquisition in this case. Therefore, when you deselect this checkbox, you can run the tests only once on existing data.
- 5 (optional) Describe the test for future reference. The specified **User Comments** will appear on the HTML report which is generated for the test.





Next · "Selecting Tests" on page 29

5 Selecting Tests



1 Click the **Select Tests** tab and then select the tests you want to run.

The tests displayed in this tab vary depending on the memory bus type that you.

The tests displayed in this tab vary depending on the memory bus type that you selected in the $\mathbf{Set} \ \mathbf{Up} \ \mathsf{tab}$.

The following table lists the tests available for the memory bus types.



Tests Available With B4661A License (DDR Memory Type)

DDR1, 2 tests DDR4 tests DDR4 tests

DDR/LPDDR Tests

ACTIVATE to PRECHARGE/Auto-PRECHARGE must be <= tRASmax

ACTIVATE to PRECHARGE must be >= tRASmin

ACTIVATE to READ/WRITE must be >= tRCD

PRECHARGE to ACTIVATE must be >= tRP

READ to PRECHARGE must be >= tRP

READ to WRITE must be >= tDRW

WRITE to PRECHARGE must be >= tDWP

WRITE to READ must be >= tDWR

WRITE to READ must be >= tDWR

WRITE to READ must be >= tDWR

WRITE to RAD must be >= tBFC

ACTIVATE (afferent banks) must be >= tRRD

READ or WRITE TEAD must be >= tRFC

ACTIVATE to ACTIVATE (different banks) must be >= tRRD

READ or WRITE to an active bank

ACTIVATE to an active bank

ACTIVATE to a ACTIVATE (same bank) must be >= tRC

Mode Register Set command to Mode Register Set command >= tMRD

Refresh tests

REFRESH cmd to REFRESH cmd must be <= tREFI * 9

ACTIVATE to PRECHARGE/Auto-PRECHARGE must be <= tRASmax ACTIVATE to PRECHARGE must be >= tRASmin ACTIVATE to READ/WRITE must be >= tRCD PRECHARGE to ACTIVATE must be >= tRP READ to PRECHARGE must be >= tRTP READ to WRITE must be >= tDRW WRITE to PRECHARGE must be >= tDWP WRITE to READ must be >= tDWR WRITE to WRITE, READ to READ must be >= tCCD REFRESH to non-NOP/DES must be >= tRFC ACTIVATE to ACTIVATE (different banks) must be >= tRRD Four ACTIVATE window (different banks) must be >= tFAW READ or WRITE to an inactive row REFRESH to an active bank ACTIVATE to ACTIVATE (same bank) must be >= tRC Mode Register Set command to Mode Register Set command >= tMRD Mode Register Set command to valid command >= tMOD REFRESH cmd to REFRESH cmd must be <= tREFI * 9

Long cal (normal operation) to valid command must be >= tZQoper Powerdown and Self Refresh tests REF command to power down entry >= tREFPDEN Read command to power down entry >= tRDPDEN Write command to power down entry >= tWRPDEN Exit reset from CKE high to valid command >= tXPR SelfRefreshExit to Valid command with DLL <tXSDLL Exit Precharge Power Down with DLL to any valid command <tXPDLL Calibration Tests Short cal (normal operation) to valid command must be >= tZQCS

ACTIVATE to PRECHARGE must be >= tRASmir

ACTIVATE to READ/WRITE must be >= tRCD PRECHARGE to ACTIVATE must be >= tRP READ to PRECHARGE must be >= tRTP READ to WRITE must be >= tDRW WRITE to WRITE (same bank group), READ t

REFRESH to non-NOP/DES must be >= tRFC Four ACTIVATE window (different banks) must be >= tFAW READ or WRITE to an inactive row
REFRESH to an active bank
ACTIVATE to an active bank ACTIVATE to ACTIVATE (same bank) must be >= tRC Mode Register Set command to Mode Register Set command >= tMRI Refresh tests REFRESH cmd to REFRESH cmd must be <= tREFI * 9 Powerdown and Self Refresh tests REF command to power down entry >= tREFPDEN Read command to power down entry >= tRDPDEN ■ Write command to power down entry >= tWRPDEN Exit reset from CKE high to valid command >= tXPR SelfRefreshExit to Valid command with DLL <tXSDLL Exit Precharge Power Down with DLL to any valid command <tXPD Calibration Tests Short cal (normal operation) to valid command must be >= tZQCS

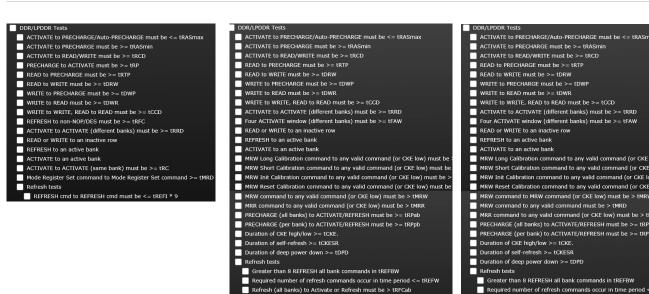
Refresh (all banks) to Activate or Refresh must be > tRFCab Refresh (per bank) to Activate (same bank) or Refresh must

Powerdown and Self Refresh tests

Exit self-refresh to valid command >= tXSR

Exit power down to valid command >= tXP





Some things to consider while selecting tests:

Powerdown and Self Refresh tests

Exit self-refresh to valid command >= tXSR
Exit power down to valid command >= tXP

- · Some tests might not make sense for your system. Do not select those tests.
- · Checking a parent node/group will check all available sub-groups/tests.

Refresh (per bank) to Activate (same bank) or Refresh must be > tRFCpb

- Unchecking a parent node/group will uncheck all sub-groups/tests.
- · A parent node is checked if all subgroups are checked.
- · A parent node is unchecked if ANY subgroup is unchecked.

When Tests Have Already Been Run



The marks have the following meanings:

Marks	Meanings
✓	The test passed.
×	The test failed.
0	The test has not been run, or no tests in the group have been run.
•	The test is currently running.
0	Some tests in the group have run and passed.
•	Some tests in the group have run and failed.
•	Some tests in the group have passed and some have failed; not all of the tests have run.
•	All tests in the group have run and passed.
•	All tests in the group have run and failed.

See Also

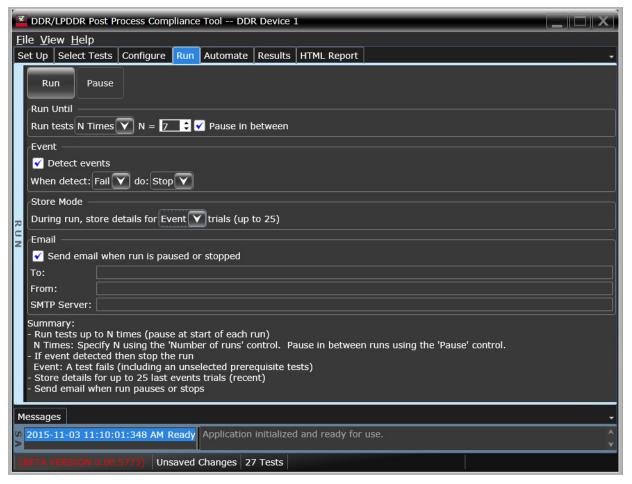
- · "To set the test limits" on page 20 (for information on how to calculate the limits)
 - "About the Tool" on page 11 (for an overview of the tests performed)

Next · "Configuring Tests" on page 19

6 Running Tests

You can use the \mathbf{Run} tab to specify how the tests should be run and then run the tests as per these settings.

You can run the tests once or repetitively.



To run the selected tests:

- 1 Click the Run tab.
- 2 Configure the settings for running the tests.
 - a From the **Store Mode** section, select which trial results from the test run(s) you want to store. You can store results for a maximum of 25 trials.
 - b From the **Run Until** section, select the number of times you want to run the tests. Following options are available:
 - Once The tests are run once.



- N Times- The tests are run repetitively for the number of times specified in the Number of Runs field.
- Forever- The tests are run repetitively until you press the Stop button.

If you select **N Times** or **Forever**, make sure you select the **Automatically acquire new logic analyzer** data when running tests checkbox in the **Set Up** tab.

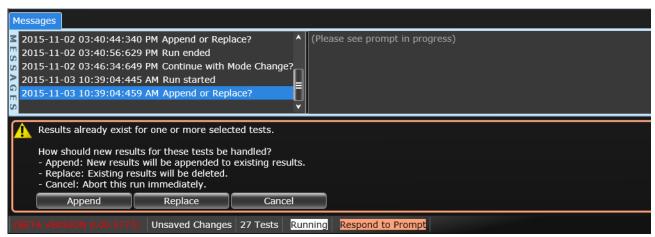
- c On selecting the **N Times** option, the **Pause in between** checkbox is displayed. Select this checkbox to instruct the tool to pause the test run after the completion of each run in the repetitive run.
- d Select the **Send email when run is paused or stopped** checkbox in the **Email** section to instruct the tool to send a notification email with the information about the test run when the test run completes or pauses. You can specify the SMTP Server and the email address to which email should be sent in the designated place when this checkbox is selected. You can also specify the sender's email address.
- e In the **Event** section, select the **Detect Event** checkbox to instruct the tool to perform a specified action when the specified event is detected in the test run. On selecting this checkbox, a listbox is displayed with this checkbox. From this listbox, you can select either Pause or Stop to pause or stop the test run when the selected event is detected during a test run.
- f When you select Event in the **Store Mode** section or select the **Detect Event** checkbox, the **When detect:** listbox is displayed to allow you to select the event. When the selected event occurs in the test run, the specified action is performed if the **Detect Event** checkbox is selected or the details for the event are stored if the **Store Mode** is set to **Event**. You can select from the following events:
 - Pass Perform the event action or store the event details when a test passes.
 - Fail Perform the event action or store the event details when a test fails.
 - Margin < N Perform the event action or store the event details when a test result margin is less than the specified minimum required margin percentage.

At times, you may receive warning messages when the selected event does not logically matches with the selected Store Mode. For instance, if the **Store Mode** is **Best**, then you can only use **Pass** as the event. Similarly, if the store mode is **Worst**, you cannot use **Pass** as the event. The tool automatically corrects the event selection in such cases.

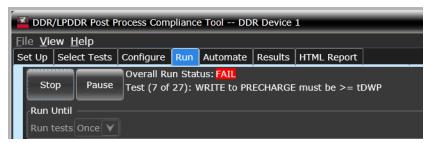
While you select the test configurations, the tool automatically keeps documenting the test configurations for your reference in the open listbox in this tab. The **Message** tab displays the list of actions and any warnings if generated.

- 3 Run the tests. There are several ways to run the selected tests:
 - · Click in the toolbar. to run all the selected tests.
 - Select a branch in the Select Tests tab and then click in the toolbar to repeatedly run only
 the tests of the selected branch.
 - · Click the big Run button in the Run tab.
- 4 If there are existing test results, you are asked if you would like to keep them or re-test (delete) them.

If you would like to keep the existing test results to compare against new results, click **Append**. Click **Replace** if you would like to delete the existing test results.



5 While the tests are running, status dialogs appear to inform you about the test progress.



When the tests are complete, Results tab is automatically displayed.

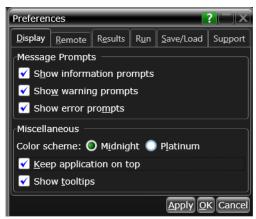
See Also • "To set the display preferences" on page 36

Next · "Viewing Results" on page 41

To set the display preferences

Information, warning, and error conditions can occur while running tests. The display preferences let you choose whether message dialogs are shown. And, there are other display preferences that affect what happens as tests are run.

- 1 From the DDR/LPDDR Post Process Compliance Tool's menu, choose View > Preferences....
- 2 In the Preferences dialog, select the **Display** tab.



- 3 In the Display tab, you can choose to show the following types of message prompts:
 - · Information prompts.
 - · Warning prompts.
 - · Error prompts.

NOTE

Messages that require you to make a choice, such as "OK/Cancel" and "Yes/No" are always enabled.

- 4 Also, you can choose to:
 - · Change the Color Scheme— Choose a background color from Midnight and Platinum options.
 - **Keep application on top** Always keep the application's main dialog on the top of the logic analyzer application. Note that the mid-run dialogs are always displayed on the top.
 - Show tooltips By enabling this option, the tooltips appear as you move the pointer over various controls in the application.
- 5 Click **Apply** to save the changes and click **OK** to close the Preferences dialog.

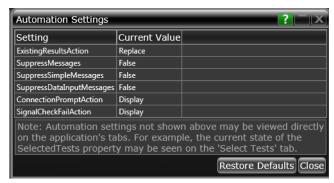
7 Automating the Tests

In the **Automate** tab, you can automate the required tests by selecting either of the following options from the **Execute commands from** section:

- Scripts
- · Files

Prerequisites

1 Click **Settings**. The Automation Settings window appears.



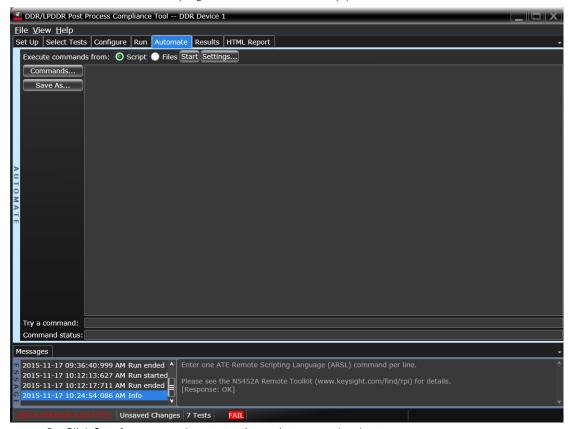
2 Check and change (if required) the appropriate settings and click **Close**.



Automation by Scripts

Perform the following steps to automate the tests by scripts:

1 Write the automation programs/commands in the top pane.

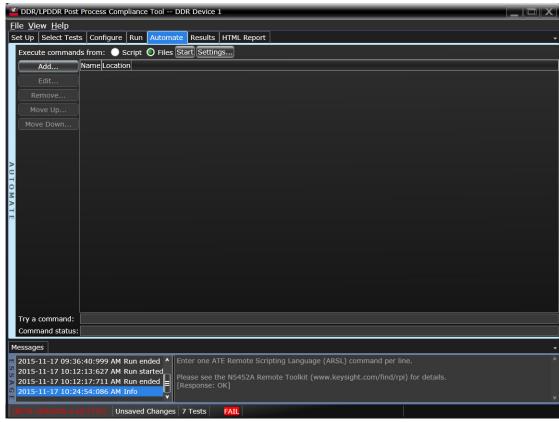


- 2 Click **Save As...** to save the automation script on your local system.
- 3 Click Start.

Automation by Files

Perform the following steps to automate the tests by files:

1 Click **Add...** to load the required file. The loaded file is displayed in the upper pane.

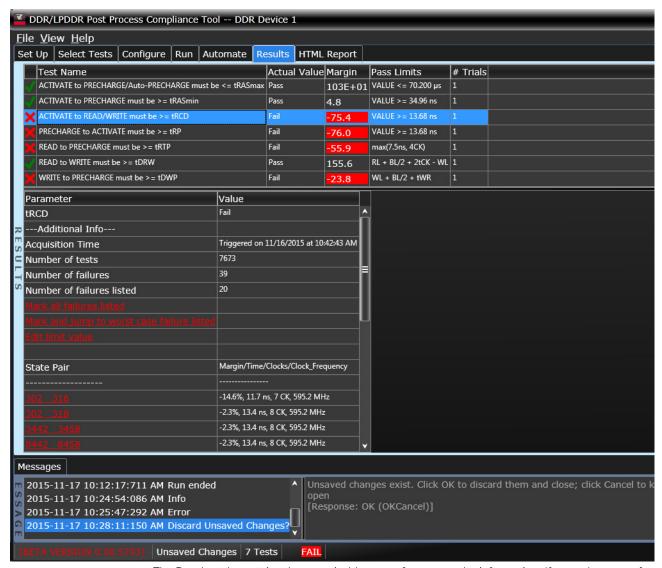


2 Click Start.

7 Automating the Tests

8 Viewing Results

1 Click the **Results** tab.



The Results tab contains three re-sizable panes for test results information. If you select one of the tests in the top pane, details and reference images (if any) are shown in the lower panes.

TIP

A quick way to reset all configuration options and delete all test results is to create a new project (see page 53). The new project will have default configuration options.



For each individual test that you selected to run, the tool reports the total number of failures that occurred for that specific test. It can show up to a maximum of 250 failures in the Details screen for an individual test.

Each limit is measured as the time between two states. Each logic analyzer state has a number and a timestamp. In case of a failure, the numbers of the two states will be reported. Note that the time stamps are only as good as the time stamp resolution of the logic analyzer card being used (this resolution may be as coarse as 2ns; see the Specifications and Characteristics in the logic analyzer's Online help for details).

If a test case is not encountered in the logic analyzer trace:

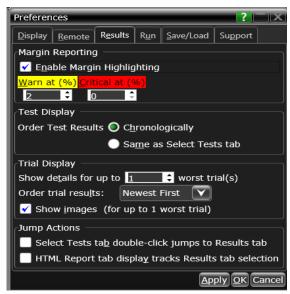
- In the details for the test, the number of tests will be 0.
- · For limit tests, the "Actual Value" column will display "N/A."
- · For pass/fail tests, the "Actual Value" column will display "Pass."

See Also · "To change margin thresholds" on page 43

Next · "Viewing/Exporting/Printing the Report" on page 45

To change margin thresholds

- 1 From the DDR/LPDDR Post Process Compliance Tool's menu, choose View>Preferences....
- 2 In the Preferences dialog, select the **Results** tab.



- 3 In the Margin Reporting area, you can:
 - · Enable or disable margin highlighting.
 - · You can change the percent of margin at which to give warnings or critical failures.
- 4 Click **OK** to close the Preferences dialog.

NOTE

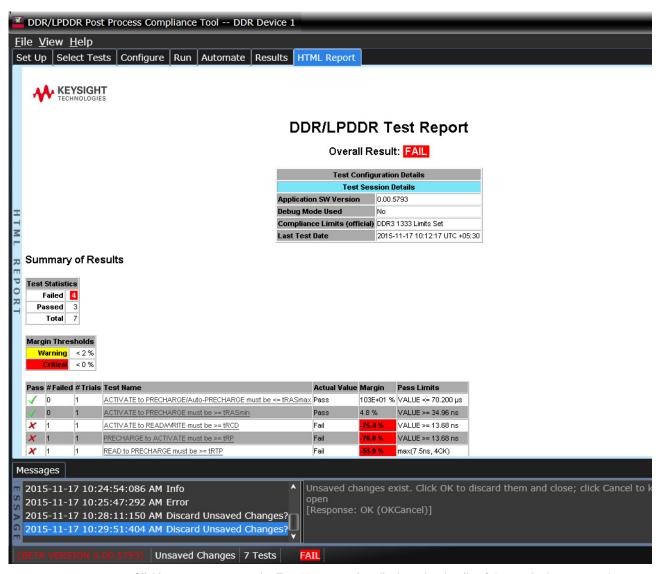
The DDR/LPDDR Post Process Compliance Tool runs the tests one time, so the Trial display options do not apply.

You can set the display order of test result in **Test Display** section.

8 Viewing Results

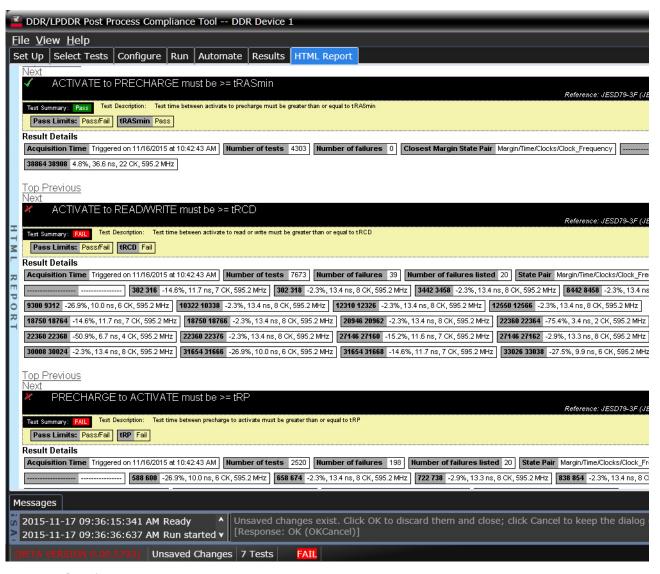
9 Viewing/Exporting/Printing the Report

To view the HTML test report, click the Html Report tab.



Clicking on any tests under Test Name section displays the details of the particular test result.





See Also • "To export the report" on page 47

"To print the report" on page 49

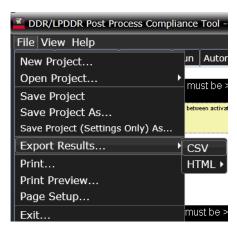
Next · "Saving Test Projects" on page 51

To export the report

1 From the DDR/LPDDR Post Process Compliance Tool's menu, choose **File > Export Results**. There are two options for exporting the HTML test report: CSV or HTML.

To export results in CSV (comma-separated values) format

Select the CSV option to export the results as a comma-separated list of values.



The data format is shown in the first line of the exported *.csv file.

```
Test ID, Test Name, Measured Item, Trial 1 Value

100, "ACTIVATE to PRECHARGE/Auto-PRECHARGE must be < tRASmax", Number of t

ests ,"9"

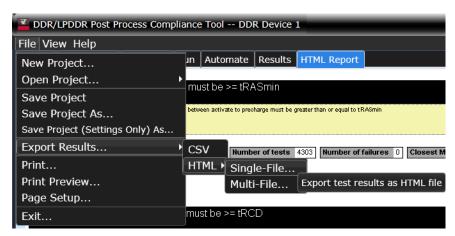
100, "ACTIVATE to PRECHARGE/Auto-PRECHARGE must be < tRASmax", Number of f

ailures ,"0"

100, "ACTIVATE to PRECHARGE/Auto-PRECHARGE must be < tRASmax", Actual Value, "4.92E-05"

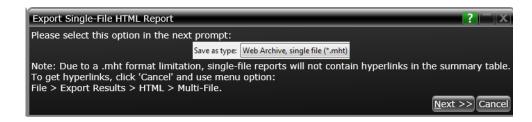
100, "ACTIVATE to PRECHARGE/Auto-PRECHARGE must be < tRASmax", Margin, "29.9"
```

To export the report in HTML format



There are two options for exporting HTML format test reports:

• Single-File — To save a single-file report, use the "save as" type "Web Archive, single file (.mt)".



NOTE

Single-file reports will not contain hyper-links in the summary table (due to a .mht format limitation). If you want these hyper-links, use the multi-file format.

Multi-File — If your report is large and you would like to use links within the report, select the HTML>Multi-File option. Selecting the multi-file option exports the results as a set of separate image and HTML files. It creates a folder with the specified name that may be copied to any computer.

To view the exported report, open the HTML file stored in the folder.

To print the report

- To preview the HTML test report printout, choose File>Print Preview... from the menu.
- To print the HTML test report, choose File > Print... from the menu.

9 Viewing/Exporting/Printing the Report

10 Saving Test Projects

To save test settings and results to the current project directory:

1 Choose File>Save Project from the menu.

To save test settings and results to a new project directory:

- 1 Choose File>Save Project As... from the menu.
- 2 In the Save Project As... dialog, enter the device name and location.

 Project files will be saved in a directory whose name is the device name.
- 3 Click OK.

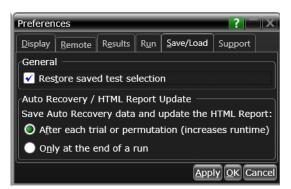
See Also

"To set AutoRecovery preferences" on page 52



To set AutoRecovery preferences

- 1 From the DDR/LPDDR Post Process Compliance Tool's menu, choose View>Preferences....
- 2 In the Preferences dialog, select the **Save/Load** tab.



- 3 In the AutoRecovery/HTML Report Update section, you can choose:
 - To auto-save results after each trial or permutation even if the entire multi-trial is not completed. This option enables full recovery.
 - · To auto-save results only upon the completion of the entire multi-trial.
- 4 Click **Apply** to save the changes and click **OK** to close the Preferences dialog.

11 Creating or Opening a Test Project

To create a new test project:

Choose File>New Project... from the menu.
 A new, empty project, with all the default settings is created.

To open an existing test project:

- 1 Choose File>Open Project... from the menu.
- 2 In the Open dialog, browse to a test project directory and select the desired ".proj" file.
- 3 Click Open.

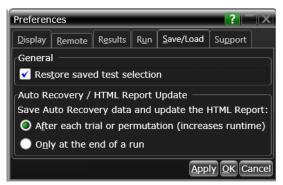
See Also · "To set load preferences" on page 54

Next · "Setting Up the Test Environment" on page 27



To set load preferences

- 1 From the DDR/LPDDR Post Process Compliance Tool's menu, choose View>Preferences....
- 2 In the Preferences dialog, select the **Save/Load** tab.



- 3 In the Save/Load tab, you can choose to restore saved test selections when loading a project.
- 4 Click **Apply** to save the changes and click **OK** to close the Preferences dialog.

Index

A about, 11 activate limit set, 25 ASR, 11 Automate, 37 AutoRecovery preferences, 52	limit set, restore, 24 limitations, 11 load preferences, 54 M margin thresholds, changing, 43	test project, saving, 51 test report (HTML), viewing/exporting/printing, 45 tests, configuring, 19 tests, running, 33 tests, selecting, 29 tests, viewing results, 41 toolbar viewing/hiding, 17
C clock speed, 27 comma-separated value (CSV) format, export results, 47 configuring tests, 19 create limit set, 24 creating test project, 53 critical at percent of margin, 43 CSV (comma-separated value) format, export results, 47 CTC commands, 27	multi-file HTML, export results, 48 O on-the-fly burst length, 11 opening test project, 53 P PASR, 11 preferences, display, 36 preferences, report, 43 preferences, save/load, 52, 54 preview print, 49 printing HTML test report, 49 project, creating or opening, 53	toolbar, viewing/hiding, 17 tooltips, show, 36 U unavailable tests, 29 V viewing HTML test report, 45 viewing test results, 41 W warn at percent of margin, 43 warning dialogs, 36
display preferences, 36	project, saving, 51	
edit limit set, 24 enable margin reporting, 43 error dialogs, 36 exporting the report, 47 HTML format, export results, 47	refresh limit set, 25 report (HTML), viewing/exporting/printing, 45 report preferences, 43 report, exporting, 47 report, printing, 49 results, viewing test, 41 running tests, 33	
HTML test report, viewing/exporting/printing, 45	S	
I information dialogs, 36 invert scope display, 36 K keep application on top, 36	save/load preferences, 52, 54 saving test project, 51 selecting tests, 29 self refresh, 11 set up, 27 show tooltips, 36 single-file HTML, export results, 47 starting DDR post process compliance tool, 15	
L	Т	
limit set, activate/refresh, 25 limit set, create/edit, 24	test project, creating or opening, 53	

Index

